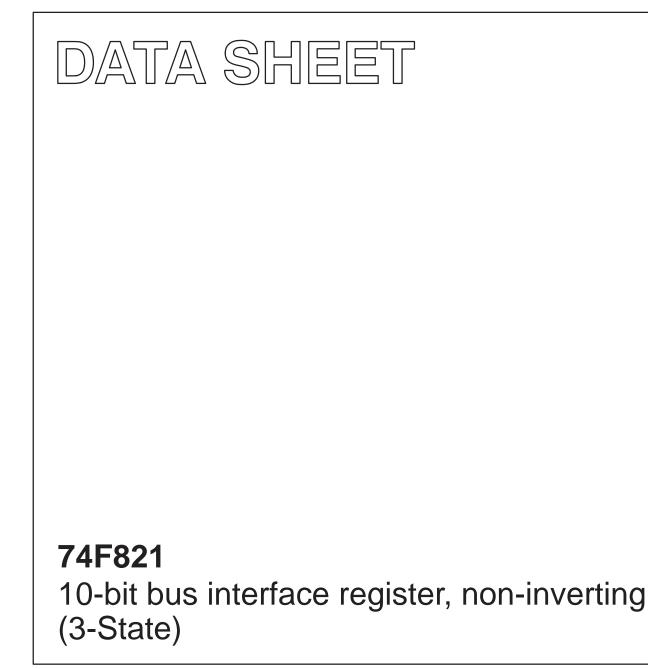
# INTEGRATED CIRCUITS



Product data sheet Replaces data sheet 74F821/822/823/824/825/826 of 1996 Jan 05

2004 Jul 22



## 74F821

## **FEATURES**

- High speed parallel registers with positive edge-triggered D-type flip-flops
- High performance bus interface buffering for wide data/address paths or buses carrying parity
- High-impedance PNP base inputs for reduced loading (20 μA in HIGH and LOW states)
- I<sub>IL</sub> is 20 μA versus 1000 μA for AM29821 series
- Buffered control inputs to reduce AC effects
- Ideal where high speed, light loading, or increased fan-in as required with MOS microprocessor
- Positive and negative over-shoots are clamped to ground
- 3-State outputs glitch free during power-up and power-down
- Slim Dip 300 mil package
- Broadside pinout compatible with AMD AM 29821
- Outputs sink 64 mA and source 24 mA

#### DESCRIPTION

The 74F821 bus interface register is designed to eliminate the extra packages required to buffer existing registers and provide extra data width for wider data/address paths of buses carrying parity.

The 74F821 is a buffered 10-bit wide version of the popular 74F374/74F534 functions.

ТҮРЕ	TYPICAL f <sub>max</sub>	TYPICAL SUPPLY CURRENT (TOTAL)
74F821	180 MHz	75 mA

## INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dn Data inputs		1.0/1.0	20 μA/0.6 mA
СР	CP Clock input		20 μA/0.6 mA
OE Output enable input (active-LOW)		1.0/3.0	20 μA/1.8 mA
Qn Data outputs		1200/106.7	24 mA/64 mA

NOTE: One (1.0) FAST unit load is defined as: 20  $\mu$ A in the HIGH state and 0.6 mA in the LOW state.

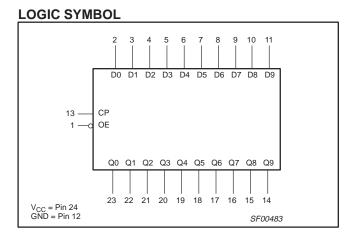
#### **ORDERING INFORMATION**

Commercial range:  $V_{CC}$  = 5 V ± 10 %;  $T_{amb}$  = 0 °C to +70 °C

Type number	Package	<sup>a</sup> ackage					
	Name	Description	Version				
N74F821D	SO24	plastic small outline package; 24 leads; body width 7.5 mm	SOT137-1				
N74F821N	DIP24	plastic dual in-line package; 24 leads (300 mil)	SOT222-1				

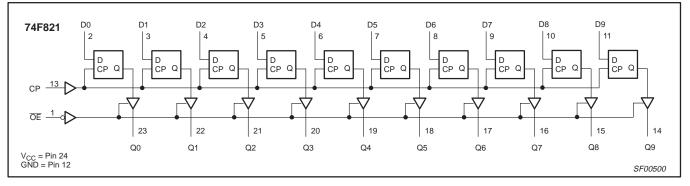
PIN CONFIGURATION					
OE 1	24 Va	cc			
D0 2	23 Q0	)			
D1 3	22 Q1				
D2 4	21 Q2	2			
D3 5	20 Q3	3			
D4 6	19 Q4	Ļ			
D5 7	18 Q5	5			
D6 8	17 Q6	3			
D7 9	16 Q7	7			
D8 10	15 Q8	3			
D9 11	14 Q9	)			
GND 12	13 CF	0			
	SF00482				

# 74F821



IEC/IEEE SYMBOL				
IEC/IEEE SYMBOL   1 13   13 2   3 4   5 6   7 8	EN1 > G2 2D [	> 1 \(\neg \)	23 22 21 20 19 18 17	
9			16	
10			15	
<u></u>			14_	
			1	SF00484

## LOGIC DIAGRAM



## **FUNCTION TABLE**

	INPUTS		OUTPUTS	OPERATING MODE			
OE	СР	Dn	Q	OFERATING MODE			
L	$\uparrow$	I	L	Load and read data			
L	$\uparrow$	h	Н				
L	1	Х	NC	Hold			
Н	Х	Х	Z	High-impedance			

H = HIGH-voltage level

= HIGH state must be present one setup time before the LOW-to-HIGH clock transition h

L = LOW-voltage level

LOW state must be present one setup time before the LOW-to-HIGH clock transition L =

NC= No change

X = Don't care

= High-impedance "off" state

Z ↑ = LOW-to-HIGH clock transition

**↑** = Not LOW-to-HIGH clock transition

74F821

## **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limit set forth in this table may impair the useful life of the device.

Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V <sub>CC</sub>	Supply voltage	-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage	-0.5 to +7.0	V
I <sub>IN</sub>	Input current	-30 to +5	mA
V <sub>OUT</sub>	Voltage applied to output in HIGH output state	–0.5 to $V_{CC}$	V
I <sub>OUT</sub>	Current applied to output in LOW output state	128	mA
T <sub>amb</sub>	Operating free-air temperature range	0 to +70	°C
T <sub>stg</sub>	Storage temperature range	-65 to +150	°C

## **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER		UNIT		
STMBOL		MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub>	HIGH-level input voltage	2.0	-	-	V
V <sub>IL</sub>	LOW-level input voltage	-	-	0.8	V
l <sub>lk</sub>	Input clamp current		-	-18	mA
I <sub>OH</sub>	HIGH–level output current	-	-	-24	mA
I <sub>OL</sub>	LOW-level output current	-	-	64	mA
T <sub>amb</sub>	Operating free-air temperature range		-	+70	°C

74F821

## **DC ELECTRICAL CHARACTERISTICS**

(Over recommended operating free-air temperature range unless otherwise noted.)

	PARAMETER		TEST CONDITIONS <sup>1</sup>			LIMITS			
SYMBOL						MIN	TYP <sup>2</sup>	MAX	UNIT
				15	± 10 %V <sub>CC</sub>	2.4	-	-	V
Maria			V <sub>CC</sub> = MIN; V <sub>II</sub> = MAX;	I <sub>OH</sub> = -15 mA	$\pm 5$ %V <sub>CC</sub>	2.4	-	-	V
V <sub>OH</sub>	HIGH-level output voltage		$V_{IH} = MIN$	I <sub>OH</sub> =24 mA	$\pm$ 10 %V <sub>CC</sub>	2.0	-	-	V
				$I_{OH} = -24 \text{ IIIA}$	$\pm 5$ %V <sub>CC</sub>	2.0	-	-	V
M			$V_{CC} = MIN;$		± 10 %V <sub>CC</sub>	-	-	0.55	V
V <sub>OL</sub>	LOW-level output voltage	/-level output voltage $V_{IL} = MAX; V_{IH} = MIN$	I <sub>OL</sub> = MAX	± 5 %V <sub>CC</sub>	-	0.42	0.55	V	
V <sub>IK</sub>	Input clamp voltage		$V_{CC} = MIN; I_I = I_{IK}$			-	-0.73	-1.2	V
lı	Input current at maximum input voltage		$V_{CC} = 0 V; V_I = 7.0 V$			-	-	100	μΑ
I <sub>IH</sub>	HIGH–level input current		$V_{CC} = MAX; V_1 = 2.7 V$		-	-	20	μA	
I <sub>IL</sub>	LOW-level input current		$V_{CC} = MAX; V_{I} = 0.5 V$		-	-	-20	μΑ	
I <sub>OZH</sub>	Off–state output current, HIGH–level voltage applied		$V_{CC} = MAX; V_O = 2.7 V$		-	-	50	μΑ	
I <sub>OZL</sub>	Off-state output current, LOW-level voltage applied		$V_{CC} = MAX; V_O = 0.5 V$			-	-	-50	μA
I <sub>OS</sub>	Short-circuit output current <sup>3</sup>		$V_{CC} = MAX$			-100	-	-225	mA
		I <sub>CCH</sub>				-	75	105	mA
I <sub>CC</sub>	Supply current (total)	I <sub>CCL</sub>	V <sub>CC</sub> = MAX			-	75	105	mA
	I <sub>CCZ</sub>					-	75	115	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. 2. All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_{amb} = 25 \text{ °C}$ . 3. Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a HIGH output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

## AC ELECTRICAL CHARACTERISTICS

			LIMITS					
SYMBOL	PARAMETER	TEST CONDITION	$T_{amb}$ = +25 °C V <sub>CC</sub> = +5.0 V C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500 Ω			T <sub>amb</sub> = 0 °C V <sub>CC</sub> = +5.0 C <sub>L</sub> = 50 pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
f <sub>max</sub>	Maximum clock frequency	Waveform 1	150	180	-	140	-	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay CP to Qn	Waveform 1	4.0 4.0	6.5 6.0	8.5 8.5	4.0 3.5	9.5 9.0	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output enable time OEn to Qn	Waveform 3 Waveform 4	2.0 3.0	4.5 5.0	8.0 8.0	2.0 2.5	9.0 9.0	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output disable time OEn to Qn	Waveform 3 Waveform 4	1.5 1.5	3.5 3.5	6.5 6.5	1.5 1.5	7.5 7.5	ns

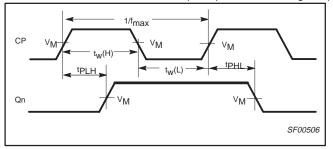
## AC SETUP REQUIREMENTS

	MBOL PARAMETER TEST CONDITION		LIMITS					
SYMBOL			l v	<sub>mb</sub> = +25 <sub>CC</sub> = +5.0 0 pF, R <sub>L</sub> =	V	V <sub>CC</sub> = +5.0	C to +70 °C ) V ± 10 % R <sub>L</sub> = 500 Ω	UNIT
			MIN	TYP	MAX	MIN	MAX	
t <sub>su</sub> (H) t <sub>su</sub> (L)	Setup time, HIGH or LOW Dn to CP	Waveform 2	1.0 1.0			1.0 1.0		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, HIGH or LOW Dn to CP	Waveform 2	2.0 2.0			2.0 2.0	-	ns
t <sub>w</sub> (H) t <sub>w</sub> (L)	CP Pulse width, HIGH or LOW	Waveform 1	3.5 3.5	-		4.0 4.0		ns

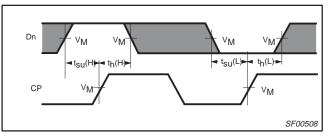
## AC WAVEFORMS

For all waveforms,  $V_M = 1.5$  V.

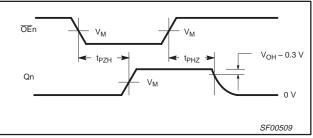
The shaded areas indicate when the input is permitted to change for predictable output performance.



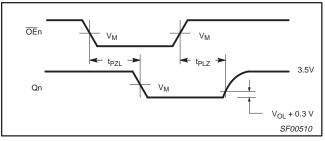
Waveform 1. Propagation delay for clock input to output, clock pulse width, and maximum clock frequency



Waveform 2. Data setup time and hold times



Waveform 3. 3-State output enable time to HIGH level and output disable time from HIGH level

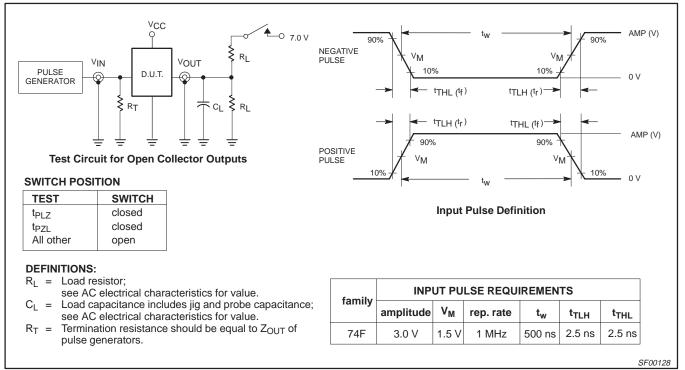


Waveform 4. 3-State output enable time to LOW level and output disable time from LOW level

74F821

## 74F821

## **TEST CIRCUIT AND WAVEFORMS**



#### SO24: plastic small outline package; 24 leads; body width 7.5 mm SOT137-1 D А Х = v 🕅 A Шγ 13 Q A٥ Å (A A. pin 1 index 12 detail X 」 ↓ ↓ ↓ ↓ ↓ е 10 mm 0 5 scale DIMENSIONS (inch dimensions are derived from the original mm dimensions) Α D <sup>(1)</sup> z<sup>(1)</sup> E<sup>(1)</sup> UNIT A<sub>1</sub> $A_2$ $A_3$ bp Q θ с е $\mathsf{H}_\mathsf{E}$ L Lp v w У max. 0.32 15.6 7.6 10.65 0.9 0.3 2.45 0.49 1.1 1.1 mm 2.65 0.25 0.25 0.25 0.1 1.27 1.4 0.1 2.25 0.36 0.23 15.2 7.4 10.00 0.4 1.0 0.4 8° $0^{\circ}$ 0.096 0.019 0.013 0.61 0.30 0.419 0.043 0.043 0.035 0.012 inches 0.1 0.01 0.05 0.055 0.01 0.01 0.004 0.004 0.089 0.014 0.009 0.60 0.29 0.394 0.016 0.039 0.016 Note 1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

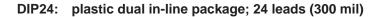
Note

OUTLINE

VERSION

SOT222-1

# 10-bit bus interface register, non-inverting (3-State)



0.045

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

IEC

0.017

JEDEC

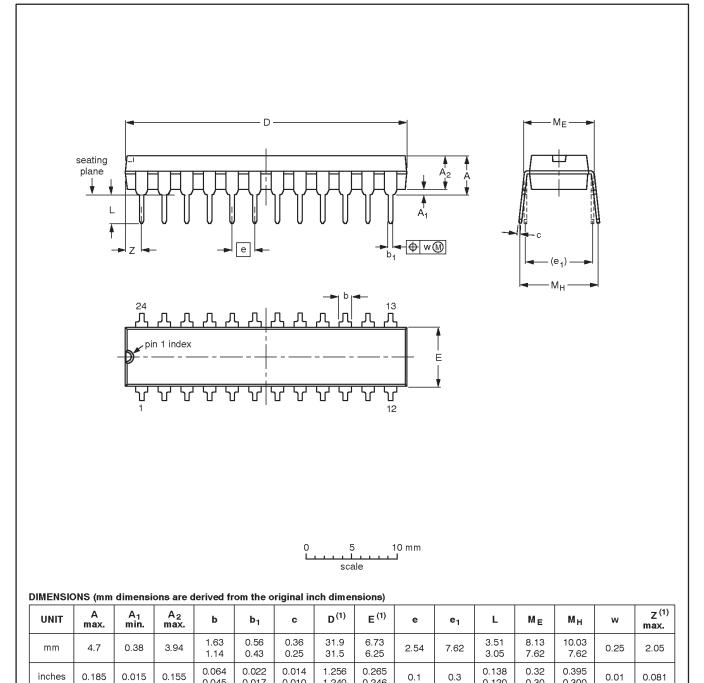
MS-001

0.010

REFERENCES

1.240

0.246



# 74F821

SOT222-1

JEITA

0.1

0.3

0.120

0.30

EUROPEAN

PROJECTION

F

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0.300

**ISSUE DATE** 

<del>-99-12-27</del>-

03-03-12

74F821

#### **REVISION HISTORY**

Rev	Date	Description
_3	20040722	(74F821_3) Product data sheet (9397 750 13819). Replaces data sheet 74F821/822/823/824/825/826 of 1996 Jan 05 (9397 750 05185).
		Modifications:
		• Remove part numbers 74F822/823/824/825/826 and references to them.
_2	19960105	(74F821–74F826_2) Product specification (9397 750 05185). ECN 853-1304 16195 of 05 January 1996.

#### Data sheet status

Level	Data sheet status <sup>[1]</sup>	Product status <sup>[2] [3]</sup>	Definitions
I	Objective data sheet	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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9397 750 13819

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